# Continued symmetry and momentum-resolved analysis of charge transfer excitation in Mott-insulator La2CuO4

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We have performed resonant inelastic x-ray scattering study on charge transfer excitations in parent materials of high-Tc superconductors, La2CuO4 and HgBaCuO4+d. Detailed polarization dependence are measured at various momenta and a strong polarization dependence that is characteristic of Raman scattering can be ruled out.

Keywords: Resonant inelastic X-ray scattering, cuprate, Mott

## 1. Purpose

We proposed to continue an ongoing effort to study the charge-transfer dynamics of strongly correlated electron systems, in particular Mott insulating and high-Tc superconducting cuprates using resonant inelastic X-ray scattering (RIXS) at the Cu Kedge.

# 2. Method

We measured the RIXS spectra of La2CuO4 and HgBa2CuO4+d in a range of scattering geometries near the Cu K edge to look for systematic changes in the RIXS cross section that may provide new information about charge-transfer and related excitations in these cuprate materials.

# 3. Result

We have studied the RIXS signal on LCO and Hg1201 in a variety of scattering geometries in an attempt to make a connection between the polarization, momentum transfer, incident energy, and energy transfer dependence of RIXS signal. Through a careful analysis which includes very special geometries, we have ruled out a strong polarization dependence that is characteristic of Raman scattering. Instead, it seems that the RIXS signal is controlled mainly by the momentum transfer.

#### 4. Conclusion

Since the momentum transfer variable is related to the real-space extent of the induced excitations, our result provides a possible in-road to studying the real space shape of induced excitations. We are currently exploring this possibility both experimentally and theoretically.

## 5. Reference

Lu et al, PRL 95, 217003 (2005) Lu et al, PRB 74, 224509 (2006)